

**Search Notes**

Application/Control No.

10/530,339

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

FURUKOSHI ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
363	16		
	20-21.18		
	49		
	97		
	131		
323	314		
	315		
	280	5/13/2006	/JH/
Search	updated	6/24/2006	/JH/

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See search report		6/26/2006	/JH/

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR